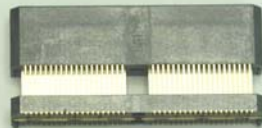


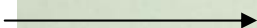


Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

QTE-040-05-L-D-A



QTE-040-04-L-D-A



QTE-040-03-L-D-A



QTE-040-02-L-D-A



QSE-040-01-L-D-A



### SUMMARY REPORT

### PART DESCRIPTION

QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A

Testing Scope : CCC/IR/DWV





Project Number: 027C		Tracking Code: 0133-027C-0498			
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively		
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier	
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8		
Test Start: 8/22/01	Test Completed: 9/20/01				

### CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

## SCOPE

To perform the following tests: CCC/IR/DWV

## APPLICABLE DOCUMENTS

Standards: EIA Publication 364

## TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001:
  - a) Sample test boards are to be ultrasonically cleaned after test lead attachment, preparation and/or soldering using the following process.
  - b) Immerse the sample test boards into the Branson 3510 cleaner which contains Kyzen Ionox HC1 (or equivalent) cleaning solution with the following conditions:
    - i) Temperature: 55 Degrees C +/- 5 Degrees C
    - ii) Frequency: 40 KHz
    - iii) Immersion Time: 5 to 10 Minutes
  - c) Sample test boards are then slowly removed and placed into the Branson 3510 cleaner which contains DI water with the following conditions:
    - i) Temperature: 55 Degrees C +/- 5 Degrees C
    - ii) Frequency: 40 KHz
    - iii) Immersion Time: 5 to 10 Minutes
  - d) Sample test boards are then removed and placed in a beaker, on a hot plate with a magnetic stirrer containing DI water warmed to 55 +/- 5 Degrees C for 1/2 to 1 minute (Use 55 C as target)
  - e) Upon removal, the sample test boards are then rinsed for 1/2 to 1 minute in room temperature free flowing DI water.
  - f) After the final rinse, the sample test boards are to be dried in an air-circulating oven for 10 to 15 minutes at 50 +/- 5 Degrees C (Use 50 C as target)
  - g) Sample test boards are then allowed to set and recover to room ambient condition prior to testing.
- 4) Any additional preparation will be noted in the individual test procedures..



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Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**FLOWCHART**

GROUP 1 1 Boards	GROUP 2A 1 Boards	GROUP 2B 1 Boards
<u>5 interdigitated contacts</u>	10 Contacts in series	2 GP in series
IR	Temp Rise	Temp Rise
DWV		
Thermal Aging		
IR		
DWV		
Cyclic Humidity		
IR		
DWV		
W V		

**Thermal Aging = EIA-364-17B Test Condition 5 at 125 deg C**

**Test Time Condition 'B' but for 300 hours**

**Cyclic Humidity =10 days with 1 cycles/day, +25 @ 92%RH to +65 @ 92%RH**

**(EIA-364-31A)**

**Temperature derated 20% and based on 125 deg C**

**Tabulate at RT, 60 and 80 degrees C**



Project Number: 027C		Tracking Code: 0133-027C-0498	
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Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

### ATTRIBUTE DEFINITION

Following is a brief, simplified description of each attribute measured.

#### THERMAL AGING

- 1) EIA-364-17B, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*, 125 degrees C, Condition B but for 300 hours.
- 2) Connectors are mated.

#### CYCLIC HUMIDITY

- 1) Reference document: EIA-364-31A, *Humidity Test Procedure for Electrical Connectors*, Method III, Test Condition B excluding Steps 7a, 7b [10 days, +25 deg C to + 65 deg C, 90% to 95% RH].

#### TEMPERATURE RISE:

- 1) When current passes through a contact, the temperature of the contact increases as a result of  $I^2R$  (resistive) heating.
- 2) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 3) The size of the temperature probe can affect the measured temperature.
- 4) Copper traces on PC boards will contribute to temperature rise:
  - a) Self heating (resistive)
  - b) Reduction in heat sink capacity affecting the heated contacts
- 5) EIA-364-70A, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at three temperature points are reported:
  - a) Ambient
  - b) 60° C
  - c) 80° C
- 8) Typically, neighboring contacts (in close proximity to maximize heat build up) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the MAXIMUM temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

#### DIELECTRIC WITHSTANDING VOLTAGE (DWV)

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon.

- 1) PROCEDURE:
  - a) Reference document: EIA-364-20B, *Withstanding Voltage Test Procedure for Electrical Connectors*.



Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

- b) Test Conditions:
  - i) Between Adjacent Contacts
  - ii) Mated or Unmated
  - iii) Mounted or Unmounted
  - iv) Rate of Application 500 V/Sec
  - v) Test Voltage (VAC) until breakdown occurs
- 2) MEASUREMENTS/CALCULATIONS
  - a) The breakdown voltage shall be measured and recorded.
  - b) The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage
  - c) The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

#### **INSULATION RESISTANCE (IR)**

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
  - a) Reference document: EIA-364-21B, *Insulation Resistance Test Procedure for Electrical Connectors*.
  - b) Test Conditions:
    - i) Between Adjacent Contacts
    - ii) Mated or Unmated
    - iii) Mounted or Unmounted
    - iv) Electrification Time 2.0 minutes
    - v) Test Voltage (VDC) corresponding to calibration settings for measuring resistances
- 2) MEASUREMENTS:
  - a) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.



Project Number: 027C		Tracking Code: 0133-027C-0498		
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively	
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A			Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly				Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01			

### TEST PROCEDURES / RESULTS

#### TEMPERATURE RISE:

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the MAXIMUM temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1 degree (computer controlled data acquisition).

#### DATA SUMMARY

- All test data is summarized in the following table. Only one set of derated curves for the samples is depicted. These curves represent the 'worst case' in that the highest temperature was detected in the respective tests (GP and Contact)

#### Two Ground Planes in Series - Indicated Temp Rise, deg C

Current, DC A	-02 Height	-03 Height	-04 Height	-05 Height
0	0	0	0	0
1.6	1.0	1.0	0.6	1.0
3.2	4.4	4.4	3.6	3.8
4.8	10.3	9.9	8.4	8.5
6.4	18.7	17.9	14.7	14.7
8.0	29.6	29.2	23.3	23.1

#### Ten Contacts in Series - Indicated Temp Rise, deg C

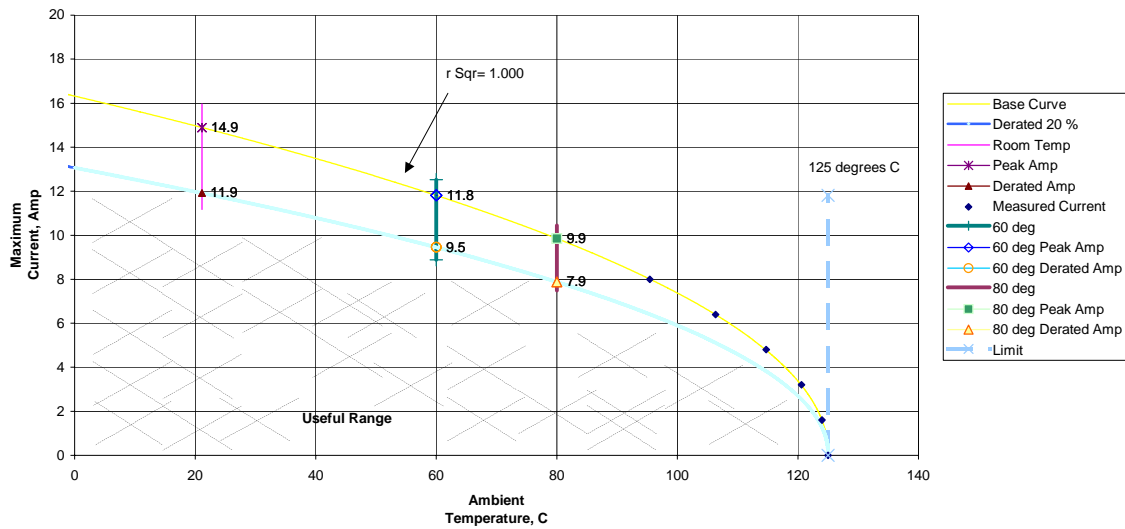
Current, DC A	-02 Height	-03 Height	-04 Height	-05 Height
0	0	0	0	0
0.4	1.4	1.8	1.5	1.5
0.8	5.8	7.3	5.8	6.1
1.2	13.3	16.0	12.9	13.4
1.6	23.3	28.0	22.5	23.3
2.0	36.2	42.8	34.7	36.1



Project Number: 027C		Tracking Code: 0133-027C-0498	
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Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

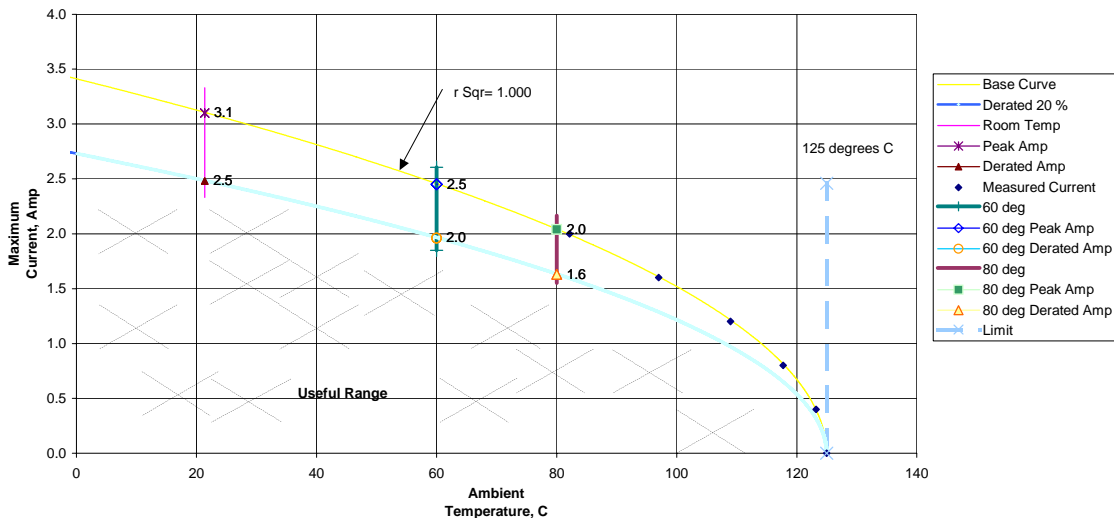
### GROUND PLANE TEMP RISE

QTE-040-02-L-D-A / QSE-040-01-L-D-A  
2 Ground Planes in Series



### CONTACTS TEMP RISE

TC0133-027C-0498  
QTE-040-03-L-D-A / QSE-040-01-L-D-A  
10 Contacts in Series





Project Number: 027C		Tracking Code: 0133-027C-0498			
Requested by: W. Ouyang		Date: 8/16/01		Product Rev: Q/H Respectively	
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A			Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly				Qty to test: 8	
Test Start: 8/22/01		Test Completed: 9/20/01			

### DIELECTRIC WITHSTANDING VOLTAGE (DWV)

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon.

1) PROCEDURE:

- a) Reference document: EIA-364-20B, *Withstanding Voltage Test Procedure for Electrical Connectors*.

2) MEASUREMENTS/CALCULATIONS

- a) The breakdown voltage shall be measured and recorded.
- b) The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
- c) The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

**Contact Description**

Series Contact is Used In: QSE

Series Contact Mates With: QTE

Test Conditions	YES	NO
Between Adjacent	X	
Mated	X	
PC Mounted	X	

Rate Of Voltage 500 V Per Sec.

Test Voltage Until Breakdown Occurs

Values in VDC

Sample #	Breakdown	Breakdown	Breakdown	DWV	DWV	DWV	Working	Working	Working
	Voltage	Voltage	Voltage	DWV	DWV	DWV	Voltage	Voltage	Voltage
	8/22/01	9/10/01	9/20/01	8/22/01	9/10/01	9/20/01	8/22/01	9/10/01	9/20/01
Average	1500	1538	1500	NA	NA	NA	NA	NA	NA
Min	1400	1450	1450	1050	1088	1088	350	363	363
Max	1600	1650	1550	NA	NA	NA	NA	NA	NA



Project Number: 027C		Tracking Code: 0133-027C-0498	
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Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**INSULATION RESISTANCE (IR)**

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

1) PROCEDURE:

a) Reference document: EIA-364-21B, *Insulation Resistance Test Procedure for Electrical Connectors*.

2) MEASUREMENTS:

a) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms

**Contact Description**

Series Contact is Used In: QSE

Series Contact Mates With: QTE

Test Conditions	YES	NO
<u>Between Adjacent</u>	X	
<u>Mated</u>	X	
<u>PC Mounted</u>	X	

**Electrification Time** *Two (2) minutes*

Values in Mohms

<u>Sample #</u>	<u>Insulation Resistance</u>	<u>Insulation Resistance</u>	<u>Insulation Resistance</u>
	<u>8/22/01</u>	<u>9/10/01</u>	<u>9/20/01</u>
	<u>Initial</u>	<u>After Thermal</u>	<u>After Humidity</u>
<b>Average</b>	100000	75000	77500
<b>Min</b>	100000	50000	10000
<b>Max</b>	100000	100000	100000



Project Number: 027C		Tracking Code: 0133-027C-0498	
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Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**DATA DWV  
INITIAL**

<b>Test Date:</b>	Initial	8/22/2001
<b>Operator:</b>		TC
<b>Temperature (C):</b>		23
<b>Humidity (RH):</b>		41%
<b>Pressure (In. Hg):</b>		29.44
<b>Equipment Code Number</b>		3

**Contact Description**

<b>Series Contact is Used In:</b>	<u>QSE</u>
<b>Series Contact Mates With:</b>	<u>QTE</u>

**Test Conditions**

	<u>YES</u>	<u>NO</u>
<u>Between Adjacent Contacts</u>	X	
<u>Mated</u>	X	
<u>PC Mounted</u>	X	

**Rate Of Applied Voltage** 500 V Per Sec.

**Test Voltage** *Until Breakdown Occurs*

<b>Board/Sample #</b>	<b>Breakdown Voltage</b>
1	1400
2	1450
3	1600
4	1550
<b>Average</b>	1500
<b>Min</b>	1400
<b>Max</b>	1600



Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
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Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**DATA DWV  
AFTER THERMAL**

<b>Test Date:</b>	After Thermal	9/10/2001
<b>Operator:</b>		TC
<b>Temperature (C):</b>		23
<b>Humidity (RH):</b>		53%
<b>Pressure (In. Hg):</b>		N/A
<b>Equipment Code Number</b>		3

**Contact Description**

**Series Contact is Used In:** QSE  
**Series Contact Mates With:** QTE

<b>Test Conditions</b>	<b>YES</b>	<b>NO</b>
<u>Between Adjacent Contacts</u>	X	
<u>Mated</u>	X	
<u>PC Mounted</u>	X	

**Rate Of Applied Voltage** 500 V Per Sec.

**Test Voltage** *Until Breakdown Occurs*

<b>Board/Sample #</b>	<b>Breakdown Voltage</b>
1	1500
2	1450
3	1650
4	1550
<b>Average</b>	1538
<b>Min</b>	1450
<b>Max</b>	1650



Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**DATA DWV  
AFTER HUMIDITY**

<b>Test Date:</b>	After Humidity	9/20/2001
<b>Operator:</b>		TC
<b>Temperature (C):</b>		23
<b>Humidity (RH):</b>		35%
<b>Pressure (In. Hg):</b>		29.42
<b>Equipment Code Number</b>		3

**Contact Description**  
**Series Contact is Used In:** QSE  
**Series Contact Mates With:** QTE

Test Conditions	<u>YES</u>	<u>NO</u>
<u>Between Adjacent Contacts</u>	X	
<u>Mated</u>	X	
<u>PC Mounted</u>	X	

**Rate Of Applied Voltage** 500 V Per Sec.  
**Test Voltage** *Until Breakdown Occurs*

<u>Board/Sample #</u>	<u>Breakdown Voltage</u>
1	1500
2	1450
3	1550
4	1500
<b>Average</b>	1500
<b>Min</b>	1450
<b>Max</b>	1550



Project Number: 027C		Tracking Code: 0133-027C-0498	
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Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**DATA IR  
INITIAL**

<b>Test Date:</b>	Initial	8/22/2001
<b>Operator:</b>		TC
<b>Temperature (C):</b>		23
<b>Humidity (RH):</b>		41%
<b>Pressure (In. Hg):</b>		29.44
<b>Equipment Code Number</b>		3

**Contact Description**

**Series Contact is Used In:** QSE  
**Series Contact Mates With:** QTE

**Test Conditions**

	<u>YES</u>	<u>NO</u>
<b><u>Between Adjacent Contacts</u></b>	<b>X</b>	
<b><u>Mated</u></b>	<b>X</b>	
<b><u>PC Mounted</u></b>	<b>X</b>	

**Electrification Time** *Two (2) minutes*

Values in Mohms

<b>Board/Sample #</b>	<b><u>Insulation Resistance</u></b>
1	100000
2	100000
3	100000
4	100000
<b>Average</b>	100000
<b>Min</b>	100000
<b>Max</b>	100000

**DATA IR**



Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**AFTER THERMAL**

**Test Date:**  
**Operator:**  
**Temperature (C):**  
**Humidity (RH):**  
**Pressure (In. Hg):**  
**Equipment Code Number**

After Thermal	8/22/2001
	TC
	23
	53%
	N/A
	3

**Contact Description**  
**Series Contact is Used In:**  
**Series Contact Mates With:**

QSE  
QTE

**Test Conditions**

	<u>YES</u>	<u>NO</u>
<u>Between Adjacent Contacts</u>	X	
<u>Mated</u>	X	
<u>PC Mounted</u>	X	

**Electrification Time** *Two (2) minutes*

Values in Mohms

<u>Board/Sample #</u>	<u>Insulation Resistance</u>
1	100000
2	100000
3	50000
4	50000
<b>Average</b>	75000
<b>Min</b>	50000
<b>Max</b>	100000

**DATA IR**



Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

### AFTER HUMIDITY

<b>Test Date:</b>	After Humidity	9/20/2001
<b>Operator:</b>		TC
<b>Temperature (C):</b>		23
<b>Humidity (RH):</b>		35%
<b>Pressure (In. Hg):</b>		29.42
<b>Equipment Code Number</b>		3

**Contact Description**

**Series Contact is Used In:** QSE  
**Series Contact Mates With:** QTE

<b>Test Conditions</b>	<b>YES</b>	<b>NO</b>
<u>Between Adjacent Contacts</u>	X	
<u>Mated</u>	X	
<u>PC Mounted</u>	X	

**Electrification Time** *Two (2) minutes*

Values in Mohms

<b>Board/Sample #</b>	<b>Insulation Resistance</b>
1	100000
2	100000
3	100000
4	10000
<b>Average</b>	77500
<b>Min</b>	10000
<b>Max</b>	100000



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## EQUIPMENT AND CALIBRATION SCHEDULES

**Description:** Temperature/Humidity Chart Recorder

**Manufacturer:** Dickson

**Model:** THDX

**Serial #:** 9316255

**Accuracy:** Temp: +/- 1C; Humidity: +/-2% RH (0 - 60%) +/- 3% RH (61 - 95%).

... Last Cal: 6/15/01, Next Cal: 6/15/02

**Description:** Digital Thermometer

**Manufacturer:** Barnant 90

**Model:** 600-2840

**Serial #:** 621994

**Accuracy:** .25% reading +/- 1.0 degree Celsius

... Last Cal: 6/25/01, Next Cal: 6/25/02

**Description:** System Power Supply

**Manufacturer:** Hewlett Packard

**Model:** HP 6033A

**Serial #:** (HP) 3329A-07330

**Accuracy:** See Manual

... Last Cal: 6/14/01, Next Cal: 6/14/02

**Description:** Multimeter /Data Acquisition System

**Manufacturer:** Keithley

**Model:** 2700

**Serial #:** 0780546

**Accuracy:** See Manual

... Last Cal: 6/14/01, Next Cal: 6/14/02

**Description:** Electronic Barometer with Pressure, Temperature, and Humidity readings

**Manufacturer:** CE

**Model:** 99760-20

**Serial #:**

**Accuracy:**

... Last Cal: NA, Next Cal: NA



Project Number: 027C		Tracking Code: 0133-027C-0498	
Requested by: W. Ouyang		Date: 8/16/01	Product Rev: Q/H Respectively
Part #: QTE-040-02-L-D-A, QTE-040-03-L-D-A, QTE-040-04-L-D-A, QTE-040-05-L-D-A, QSE-040-01-L-D-A		Lot #: 08/15/01	Tech: T. Cook Eng: J. Tozier
Part description: .8mm Double Row High Speed Connector Assembly			Qty to test: 8
Test Start: 8/22/01	Test Completed: 9/20/01		

**Description:** Temperature/Humidity Chamber

**Manufacturer:** Thermotron

**Model:** SE-1000-6-6

**Serial #:** 31808

**Accuracy:** see manual

... Last Cal: 3/27/01, Next Cal: 3/27/02

**Description:** Temperature/Humidity Chamber

**Manufacturer:** Thermotron

**Model:** SM-8-7800

**Serial #:** 30676

**Accuracy:** see manual

... Last Cal: 6/14/01, Next Cal: 6/30/02